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EIA STANDARD

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Pin Contact Stability Test Procedure for Electrical Connectors

EIA-364-116

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clause 3.35 and 4.5.31)

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Electronic Components Industry Association

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(From Standards Proposal No. 5336, formulated under the cognizance of the CE-2.0 Committee on EIA National Connector and Sockets Standards, and previously published by the DLA Land and Maritime as Department of Defense Specification MIL-DTL-38999, clause 3.35 and 4.5.31 and reaffirmed by Standards Proposal No. 5462.03.)

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